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| <b>Search Notes</b><br><br> | <b>Application/Control No.</b><br><br>10598025 | <b>Applicant(s)/Patent Under Reexamination</b><br><br>DE HAAN ET AL. |
|  | <b>Examiner</b><br><br>Kenneth Chang           | <b>Art Unit</b><br><br>4171  |

| SEARCHED |                                   |            |          |
|----------|-----------------------------------|------------|----------|
| Class    | Subclass                          | Date       | Examiner |
| 380      | 200, 203, 210, 212, 217, 236, 239 | 12/23/2008 | KWC      |
| 713      | 153, 160, 167, 170                | 12/23/2008 | KWC      |
| 725      | 60, 61, 67, 68, 70, 87, 145       | 12/23/2008 | KWC      |
| 370      | 321, 386                          | 12/23/2008 | KWC      |
| 382      | 100, 234, 235                     | 12/23/2008 | KWC      |
| 705      | 57, 59, 405                       | 12/23/2008 | KWC      |

| SEARCH NOTES   |            |          |
|--|------------|----------|
| Search Notes   | Date       | Examiner |
| Requested NPL STIC PLUS Search.  | 12/22/2008 | KWC      |
| Searched USPAT AND PGPUB Databases for Class 380 Subclasses 200, 203, 210, 212, 217, 236, 239; Class 725 Subclasses 60, 61, 67, 68, 87, 145; Class 713 Subclasses 153, 160, 167, 170; Class 370 Subclasses 321, 386; Class 382 Subclasses 100, 234, 235; Class 705 Subclasses 57, 59, 405. Class 726 | 12/23/2008 | KWC      |
| Searched NPL IEEEExplore.  | 12/23/2008 | KWC      |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

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